<table>
<tr><td rowspan="6">INFORMATION DISCLOSURE STATEMENT BY APPLICANT
(stamp: O I P E NOV 17 2006 TRADEMARK)</td><td>Attorney Docket Number</td><td>1011-67627-01</td></tr>
<tr><td>Application Number</td><td>10/781,031</td></tr>
<tr><td>Filing Date</td><td>February 17, 2004</td></tr>
<tr><td>First Named Inventor</td><td>Rajski</td></tr>
<tr><td>Art Unit</td><td>2193</td></tr>
<tr><td>Examiner Name</td><td>David H. Malzahn</td></tr>
</table>

U.S. PATENT DOCUMENTS

Copies of U.S. Patent documents do not need to be provided, unless requested by the Patent and Trademark Office. For patents, provide the patent number and the issue date. For published U.S. applications, provide the publication number and the publication date. For unpublished pending patent applications, provide the application number and the filing date.

Examiner's Initials*	Cite No. (optional)	Number	Publication Date	Name of Applicant or Patentee
DHM		5,072,178	12.10.1991	Matsumoto
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DHM		Japan	63-286780 (w/English abstract)	11.24.1988	Iwasaki et al.
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Examiner's Initials*	Cite No. (optional)	OTHER DOCUMENTS
DHM		Konemann et al., "Built-In Logic Block Observation Techniques," *IEEE Test Conference*, 6 pp. (1979).

EXAMINER SIGNATURE:	/David Malzahn/	DATE CONSIDERED:	12/13/2006

* Examiner: Initial if reference considered, whether or not in conformance with MPEP 609. Draw line through cite if not in conformance and not considered. Include copy of this form with next communication to applicant.